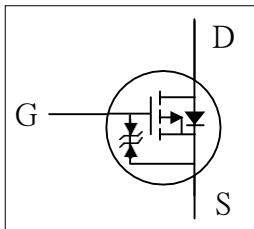
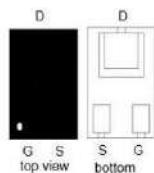


P-Channel High Density Trench MOSFET



FBP1006 (TOP view)



1. GATE
2. DRAIN
3. SOURCE

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-20V	640mΩ	800mA

ESD PROTECTION DIODE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS		UNITS
Drain-Source Voltage		V_{DS}	-20		V
Gate-Source Voltage		V_{GS}	± 12		V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	-800		mA
	$T_C = 100^\circ\text{C}$		-640		
Pulsed Drain Current ¹		I_{DM}	-2		A
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	0.69		W
	$T_C = 100^\circ\text{C}$		0.44		
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-40 to 150		°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		180	°C / W

¹Pulse width limited by maximum junction temperature.

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 100\mu\text{A}$	-20			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 100\mu\text{A}$	-0.5	-0.75	-1	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 16V$			± 30	μA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -16V, V_{GS} = 0V$			1	μA
		$V_{DS} = -16V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			10	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = -10V, V_{GS} = -10V$	-5			A
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = -1.8V, I_D = -350\text{mA}$		1300	1950	$\text{m}\Omega$
		$V_{GS} = -2.5V, I_D = -450\text{mA}$		730	950	
		$V_{GS} = -4.5V, I_D = -550\text{mA}$		530	640	
Forward Transconductance ¹	g_{fs}	$V_{GS} = -12V, I_D = -200\text{mA}$		1		S



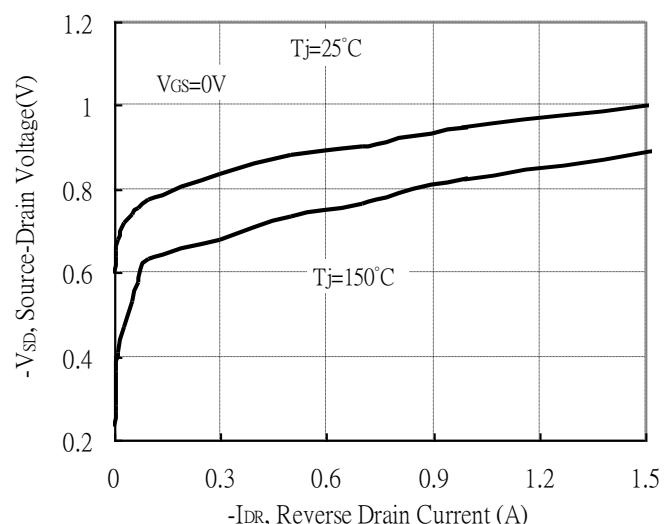
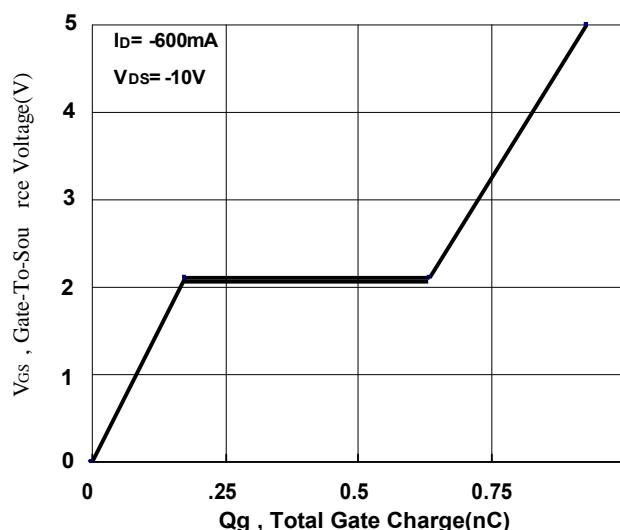
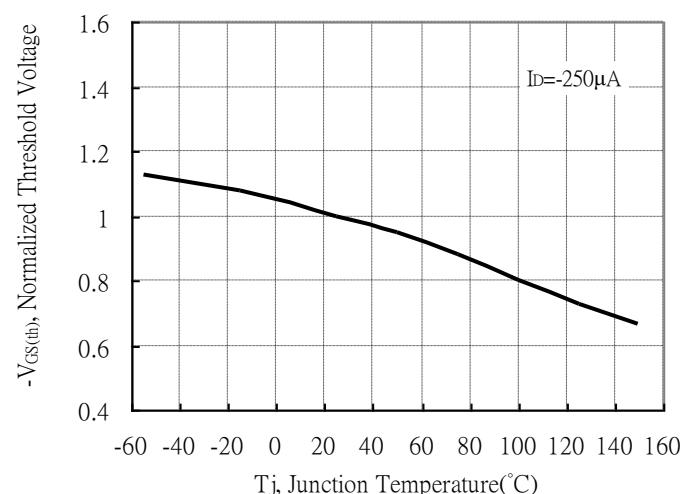
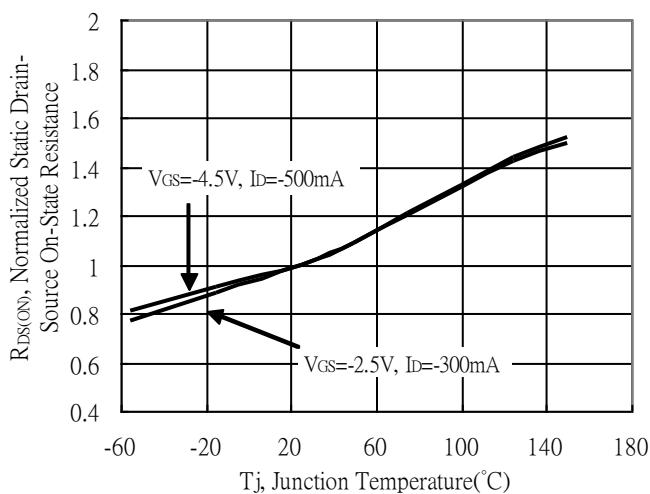
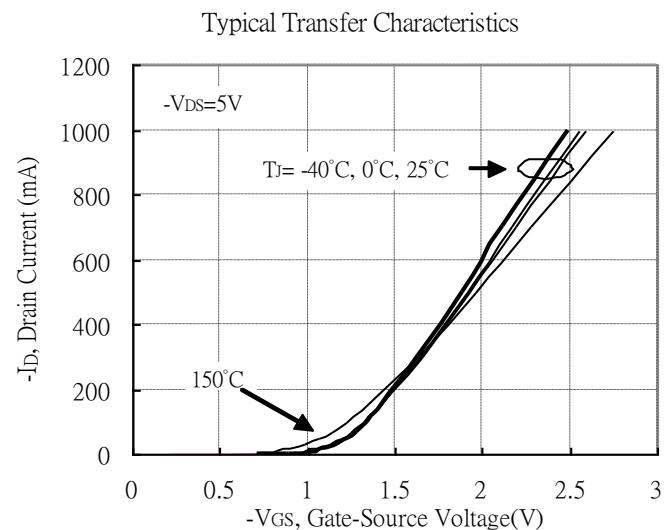
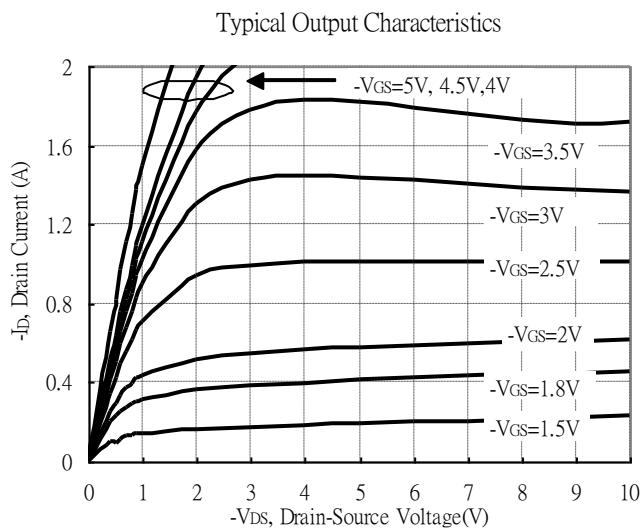
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = -25V, f = 1MHz$		58		pF
Output Capacitance	C_{oss}			5.7		
Reverse Transfer Capacitance	C_{rss}			4.4		
Total Gate Charge ²	Q_g	$V_{DS} = -10V_{(BR)DSS}, V_{GS} = -4.5V,$ $I_D = -600mA$		0.8		nC
Gate-Source Charge ²	Q_{gs}			0.2		
Gate-Drain Charge ²	Q_{gd}			0.2		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS($T_J = 25^{\circ}C$)						
Continuous Current	I_S	$I_F = -200mA, V_{GS} = 0V$		-500		mA
Forward Voltage ¹	V_{SD}			-0.85	-1.2	V

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.

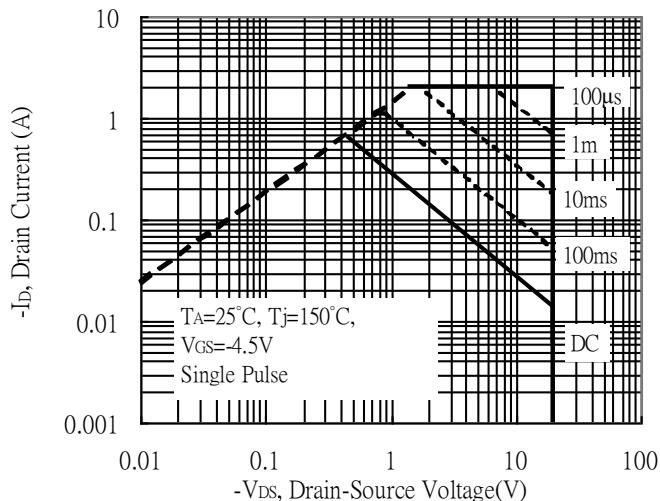
²Independent of operating temperature.

³Pulse width limited by maximum junction temperature.

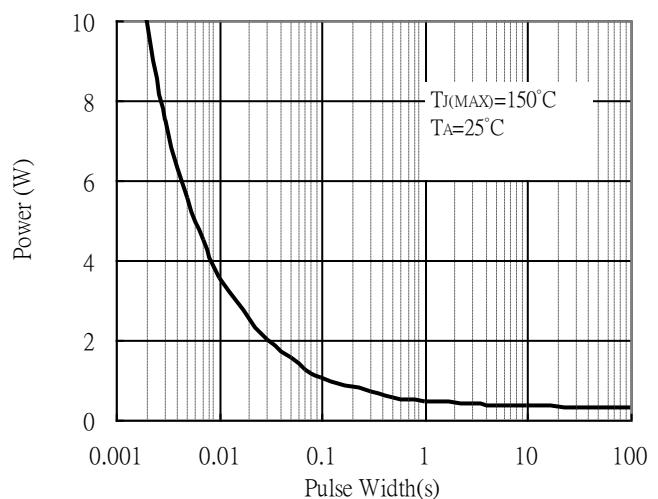
REMARK: ESD Protected Gate, 2KV HBM



Maximum Safe Operating Area



Single Pulse Power Rating, Junction to Ambient



Transient Thermal Response Curve

